HP 83000 F330 IC Test System Memory Test User Training

Technical Data

Course Overview

Learn how to set up a memory test with provided test patterns and how to customize memory test patterns. Learn to debug failures from a memory test and facilitate for address and data scrambling. In addition, learn to handle refresh requirements, to accommodate for redundancy repair, and to test high speed memories.

What You Will Learn

- Set up a memory test with provided test patterns
- Customize memory test patterns
- Debug failures from a memory test
- Facilitate for address and data scrambling
- Handle refresh requirements
- Accommodate for redundancy repair
- Test high speed memories

Specifications

Course Length

3 days

Audience

- Engineers responsible for the characterization or production testing of memory devices or devices containing embedded memory architectures.

Prerequisites

- Completion of the HP 83000 F330 User Training (E2823A+24D)
- Completion of the HP 83000 F330 Advanced User Training (E2824A+24D)
- Familiarity with methodologies of testing memory devices.

Delivery Method

Classroom, Dedicated

Format

50% lectures to discuss testing and tester concepts and their key features, and 50% lab exercises to gain practical *how-to* knowledge.

Ordering Information

To order the HP 83000 F330 IC Test System Memory Test User Training (E2830A+24D) in the U.S. call 1-800-593-6632.

HP's Customer Registration Center can provide you with price and enrollment information about scheduled courses or a dedicated course which can be customized to meet your specific needs.

Outside the U.S., contact your nearest local HP sales office.

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Classroom Training Benefits

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Available at HP Classrooms, or Your Site

Take advantage of HP's learning facilities, equipment, and interactive learning environment by attending class at an HP facility.

Or, save travel expenses and time by attending a dedicated class.

Regularly Scheduled Classes

Plan training months in advance.

Extensive Hands-on Practice

HP classroom training is characterized by extensive hands-on experience and interactive class discussion. HP classroom training pays off immediately because it is geared to real-world solutions.

Comprehensive Student Materials

Copies of course materials are provided for future reference on the job.

Course Number: **E2830A+24D (scheduled)**

HP 83000 F330 IC Test System Memory Test User Training (E2830A+24D)

Course Agenda

The course provides training on the Memory Test Application Software package. This is an optional software package for the HP 83000 F330 IC Test System.

- Introduction to Testing Memories
  - This lesson refreshes memory device technologies and test methodologies.
- Introduction to the Tester
  - Compare a traditional memory test architecture with the APG capabilities of the per-pin sequence architecture of the F330.
- A Review of Timing
  - This lesson review the wave tables and equations based timing concept of the F330 and its relationship to pattern generation for memory devices.
- Setting Up a Memory Test
  - From pin configuration through timing setup, this lesson leads to the definition of ports and to setting up a first memory test.
- Scrambling
  - Address and data scrambling is discussed in this lesson.
- Getting Results
  - Executing more elaborate test, and using the bitmap/fail memory for memory analysis are the subjects of this lesson.
  - Also discussed in this lesson is how to characterize the parametric performance of the device with shmoo plots and other characterization tools.
- APG-ALPAD
  - This lesson gives an introduction to a macro language to customize test pattern.
- Low Level ALPAD
  - Next we will introduce a C based API to implement custom specific test patterns.
- Devices with Refresh
  - How to accommodate for the refresh requirements of DRAM is the focus of this lesson.
- Redundancy Repair
  - This lesson introduces you to the algorithms needed to accomplish redundancy repair.

Course Number: E2830A+24D (scheduled)

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